Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/722,609	NAKAJIMA, AKIRA
Examiner	Art Unit
Tuan Quach	2826

SEARCHED					
Class	Subclass	Date	Examiner		
257	88, 443, 444, 686, 777, 782	3/18/2005	TQ		
257	783	3/18/2005	TQ		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (USPAT; USPGPUB; DERWENT; EPO; JPO; IBMTDB)	3/18/2005	ΤQ		
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